

**CALL FOR PAPERS**



# **LATS**2021

**22<sup>nd</sup> IEEE Latin-American Test Symposium**

Virtual Symposium, 27<sup>th</sup> - 29<sup>th</sup> October 2021

[www.lats.ttc-events.org](http://www.lats.ttc-events.org)



## CALL FOR PAPERS

The IEEE Latin-American Test Symposium (LATS) is a recognized test and fault tolerance techniques forum attended by professionals from all over the world, in particular from Latin-America, to present and discuss various aspects of system, board, and component testing as well as design, manufacturing and in-field considerations with fault tolerance in mind. Accepted papers will be submitted for inclusion into IEEE Xplore subject to meeting IEEE Xplore's scope and quality requirements. Further, the best papers of its 22<sup>nd</sup> edition will be invited to re-submit to IEEE Design&Test, Journal of Electronic Testing: Theory and Applications (JETTA - Springer) and IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (TCAD).

## Topics of interest include but are not limited to

CAD for robust circuits design  
Cross-layer reliability approaches  
Dependable system design  
Dependable Computer Architectures  
Design for Electromagnetic Compatibility (EMC)  
Design for reliability  
Design for reliability approaches for Low-Power  
Design for Robustness  
Design for Security  
Fault-based attacks and countermeasures  
Fault-tolerant and fail-safe systems  
Field Diagnosis, maintainability, and reconfiguration  
Functional safety  
IC- and system-level radiation hardening techniques  
Infrastructure, cloud computing, and wired, cellular and satellite communications

Memory test and repair  
On-line monitoring  
On-line testing techniques  
Power density and overheating issues in nanometer technologies  
Quality, yield, reliability and lifespan issues in nanometer technologies  
Reliability issues of Low-Power Design  
Robustness evaluation  
Self-Adapting design  
Self-checking circuits and coding theory  
Self-Healing design  
Self-Regulating design  
Self-test and self-repair  
Variability, Aging, EMI, and Radiation Effects in nanometer technologies

## Paper Submission Information

To encourage and facilitate discussions, participation will be limited. Those interested in presenting recent results at the symposium are invited to submit an extended abstract, one to three pages long, or a full length paper. PDF electronic submissions must be done via the symposium's webpage: [www.lats.ttc-events.org](http://www.lats.ttc-events.org)

Authors should send papers in the IEEE format. Detailed instructions are available at the symposium's webpage. The Program Committee also welcomes proposals for panels and special sessions.

For additional information, please contact our Program Co-Chairs:

Leticia Bolzani Poehls – RWTH Aachen, Germany ([leticia@poeahls.com](mailto:leticia@poeahls.com))

Fabian Luis Vargas - PUCRS, Brazil ([vargas@computer.org](mailto:vargas@computer.org))

**Submission Deadline (Title and Abstract): May 21<sup>st</sup>, 2021**

**Submission (Full paper): May 28<sup>th</sup>, 2021**

**Notification of Acceptance: July 9<sup>th</sup>, 2021**

**Camera Ready: July 30<sup>th</sup>, 2021.**

## Organizers / Sponsors:



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